Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/811,398	MEISEL ET AL.
Examiner	Art Unit
Patrick J. Lee	2878

	SEAR	RCHED	
Class	Subclass	Date	Examiner
250	207, 214VT, 214.1	8/7/06 8/0/06 8/73/06	PL
313	103CM		PL
313	105CM		PL
313	105R		PL
348	216.1		PL
348	217.1	V	PL
	,		

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
	1				

DATE 8/7/2006 8/10/2006	EXMR PL
	PL
8/10/2006	
	PL
8/23/2006	PL
	: - <del>-</del>
	8/23/2006